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(54) Title: APPARATUS AND METHOD FOR UTILIZING NONPERFECT MEMORY ELEMENTS

## (57) Abstract

Memory apparatus serving a data supplying device, the memory apparatus including a plurality of at least  $n+1$  memory elements (610-630), each memory element including a multiplicity of memory cells, wherein at least one memory cell in at least one of the  $n+1$  memory elements (610-630) is defective, and a defective memory element controlling device (640) operative to control the plurality of memory elements including a least one defective memory element so as to obtain timing at least as rapid as the timing of a plurality of  $n$  perfect memory elements without providing additional physical connections to the data supplying device.

